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November 2009

### FDY4000CZ

# Complementary N & P-Channel PowerTrench® MOSFET

### **Features**

Q1: N-Channel

- Max  $r_{DS(on)} = 0.7\Omega$  at  $V_{GS} = 4.5V$ ,  $I_D = 600$ mA
- Max  $r_{DS(on)} = 0.85\Omega$  at  $V_{GS} = 2.5V$ ,  $I_D = 500$ mA
- Max  $r_{DS(on)} = 1.25\Omega$  at  $V_{GS} = 1.8V$ ,  $I_{D} = 150$  mA

Q2: P-Channel

- Max  $r_{DS(on)} = 1.2\Omega$  at  $V_{GS} = -4.5V$ ,  $I_D = -350$ mA
- Max  $r_{DS(on)}$  = 1.6 $\Omega$  at  $V_{GS}$  = -2.5V,  $I_D$  = -300mA
- Max  $r_{DS(on)} = 2.7\Omega$  at  $V_{GS} = -1.8V$ ,  $I_D = -150$ mA
- ESD protection diode (note 3)
- RoHS Compliant

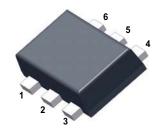


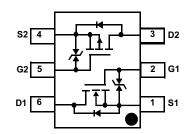
### **General Description**

This Complementary N & P-Channel MOSFET has been designed using Fairchild Semiconductor's advanced Power Trench® process to optimize the  $r_{DS(ON)}$  @  $V_{GS} \! = \! 2.5 V$  and specify the  $r_{DS(ON)}$  @  $V_{GS} \! = \! 1.8 V$ .

### **Applications**

- Level shifting
- Power Supply Converter Circuits
- Load/Power Switching Cell Phones, Pagers





### MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V <sub>DS</sub>	Drain to Source Voltage		20	-20	V
$V_{GS}$	Gate to Source Voltage		±12	±8	V
	Drain Current -Continuous (Note 1a) 600		-350	A	
ID D	-Pulsed		1000	-1000	- mA
P <sub>D</sub> Power Dissipation (Steady State) (Note 1a) (Note 1b)		(Note 1a)	625		mW
		9) 446		IIIVV	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Jaunting Temperature Range		-55 to	o 150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	200	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	280	C/VV

### **Package Marking and Ordering Information**

Device Marking	Device	Package Reel Size Ta		Tape Width	Quantity
Е	FDY4000CZ	SC89-6	7"	8mm	3000units

<b>Electrical Characteristics</b> T <sub>J</sub> = 25°C unless otherwise noted								
Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units	
Off Chara	ncteristics							
B <sub>VDSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V$ $I_D = -250\mu A, V_{GS} = 0V$	Q1 Q2	20 -20			V	
$\frac{\Delta B_{VDSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25°C $I_D$ = -250 $\mu$ A, referenced to 25°C	Q1 Q2		15 -15		mV/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 16V, V <sub>DS</sub> = 0V V <sub>DS</sub> = -16V, V <sub>DS</sub> = 0V	Q1 Q2			1 -3	μА	
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 12V, V_{DS} = 0V$ $V_{GS} = \pm 4.5V, V_{DS} = 0V$ $V_{GS} = \pm 8V, V_{DS} = 0V$	Q1 Q1 Q2			±10 ±1 ±10	μА	

### On Characteristics (note 2)

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, \ I_D = 250 \mu A$ $V_{GS} = V_{DS}, \ I_D = -250 \mu A$	Q1 Q2	0.6 -0.6	1.0 -1.0	1.5 -1.5	٧
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25°C $I_D$ = -250 $\mu$ A, referenced to 25°C	Q1 Q2		-3 3		mV/°C
r <sub>DS(on)</sub> Drain to \$	Drain to Source On Resistance	$V_{GS}$ = 4.5V, $I_{D}$ = 600mA $V_{GS}$ = 2.5V, $I_{D}$ = 500mA $V_{GS}$ = 1.8V, $I_{D}$ = 150mA, $V_{GS}$ = 4.5V, $I_{D}$ = 600mA, $T_{J}$ = 125°C	Q1		0.30 0.40 0.80 0.35	0.70 0.85 1.25 1.00	Ω
		$V_{GS} = -4.5V, I_D =350 \text{mA}$ $V_{GS} = -2.5V, I_D = -300 \text{mA}$ $V_{GS} = -1.8V, I_D = -150 \text{mA}$ $V_{GS} = -4.5V, I_D = -350 \text{mA}, T_J = 125 ^{\circ}\text{C}$	Q2		0.5 0.8 1.3 0.7	1.2 1.6 2.7 1.6	
9FS	Forward Transconductance	$V_{DS} = 5V, I_{D} = 600 \text{mA}$ $V_{DS} = -5V, I_{D} = -350 \text{mA}$	Q1 Q2		1.8 1		S

### **Dynamic Characteristics**

-					
C <sub>iss</sub>	Input Capacitance	Q1 V <sub>DS</sub> = 10V, V <sub>GS</sub> = 0V, f = 1MHz	Q1 Q2	00 00	pF
C <sub>oss</sub>	Output Capacitance	Q2	Q1 Q2	20 30	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{DS} = -10V, V_{GS} = 0V, f = 1MHz$	Q1 Q2	10 15	pF

### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	Q1 V <sub>DD</sub> = 10V, I <sub>D</sub> = 1A,	Q1 Q2	6 6	12 12	ns
t <sub>r</sub>	Rise Time	$V_{GS}$ = 4.5V, $R_g$ = 6 $\Omega$	Q1 Q2	8 13	16 23	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	Q2 $V_{DD} = -10V, I_{D} = -0.5A,$	Q1 Q2	8 8	16 16	ns
t <sub>f</sub>	Fall Time	$V_{GS}$ = -4.5V, $R_g$ = $6\Omega$	Q1 Q2	2.4 1	4.8 2	ns
Q <sub>g</sub>	Total Gate Charge	Q1	Q1 Q2	0.8 1.0	1.1 1.4	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS}$ = 10V, $I_{D}$ = 600mA, $V_{GS}$ = 4.5V	Q1 Q2	0.16 0.2		nC
$Q_{gd}$	Gate to Drain "Miller"Charge	$V_{DS}$ = -10V, $I_{D}$ = -350mA, $V_{GS}$ = -4.5V	Q1 Q2	0.26 0.3		nC

### **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units

### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0V$ , $I_S = 150mA$ (Note 2) $V_{GS} = 0V$ , $I_S = -150mA$ (Note 2)	Q1 Q2	0.7 -0.8	1.2 -1.2	V
t <sub>rr</sub>	Reverse Recovery Time	Q1 I <sub>F</sub> = 600mA, di/dt = 100A/μs	Q1 Q2	8 11		ns
Q <sub>rr</sub>	Reverse Recovery Charge	Q2 I <sub>F</sub> = -350mA, di/dt = 100A/μs	Q1 Q2	1 2		nC

### Notes

12 R<sub>0,IA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0,IC</sub> is guaranteed by design while R<sub>0,IA</sub> is determined by the user's board design.



a) 200°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 280°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

- 2: Pulse Test: Pulse Width < 300us, Duty Cycle < 2.0%
- 3: The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

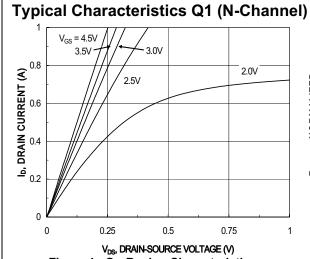
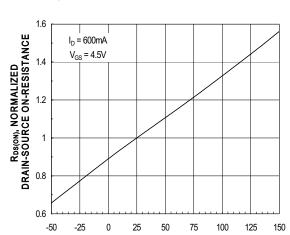


Figure 1. On-Region Characteristics



T,, JUNCTION TEMPERATURE (°C) Figure 3. Normalized on-Resistance vs. **Temperature** 

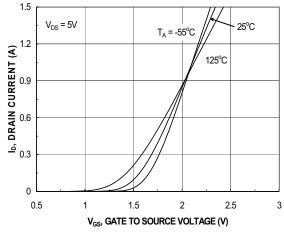
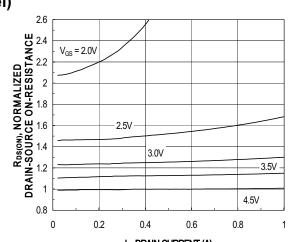


Figure 5. Transfer Characteristics



In DRAIN CURRENT (A) Figure 2. Normalized on-Resistance vs. Drain **Current and Gate Voltage** 

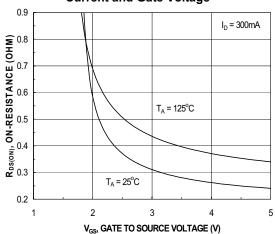


Figure 4. On-Resistance vs. Gate-to-Source Voltage

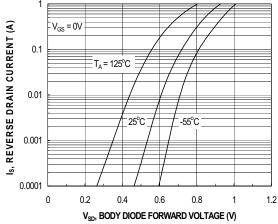


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current and Temperature

f = 1MHz

 $V_{GS} = 0 V$ 

# Typical Characteristics Q1 (N-Channel) Solved Parameteristics Q1 (N-Channel) Local Characteristics Q1 (N-Channel)

C<sub>iss</sub>

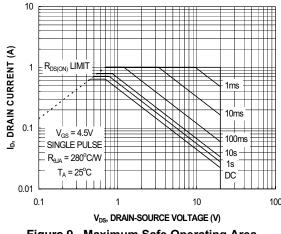
100

90

80

Figure 8. Capacitance vs. Drain to source voltage

V<sub>DS</sub>, DRAIN TO SOURCE VOLTAGE (V)



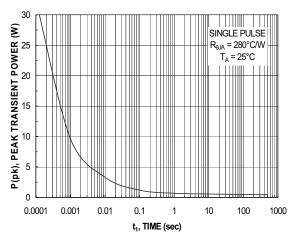


Figure 9. Maximum Safe Operating Area

Figure 10. Single Pulse Maximum Power Dissipation

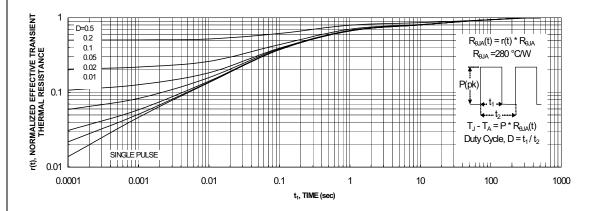


Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

# Typical Characteristics Q2 (P-Channel) 1 0.8 4.0V -3.0V -1.8V -1.8V

Figure 12. On-Region Characteristics

0.5 1 1.5 -V<sub>DS</sub>, DRAIN TO SOURCE VOLTAGE (V)

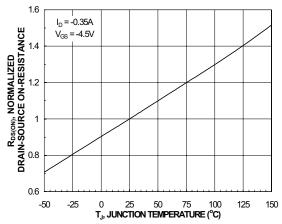


Figure 14. Normalized on-Resistance vs. Temperature

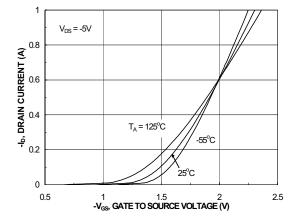


Figure 16. Transfer Characteristics

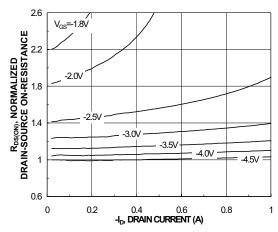


Figure 13. Normalized on-Resistance vs. Drain Current and Gate Voltage

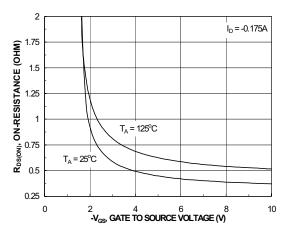


Figure 15. On-Resistance vs. Gate-to-Source Voltage

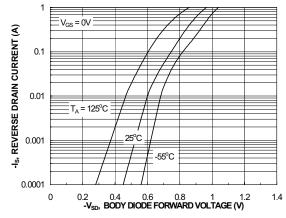


Figure 17. Source to Drain Diode Forward Voltage vs. Source Current and Temperature

### **Typical Characteristics Q2 (P-Channel)**

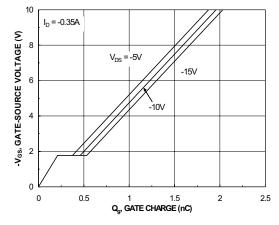


Figure 18. Gate Charge Characteristics

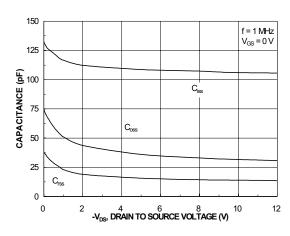


Figure 19. Capacitance vs. Drain to source voltage

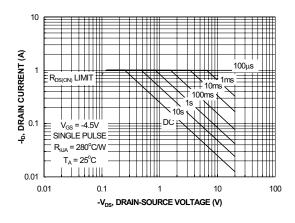


Figure 20. Maximum Safe Operating Area

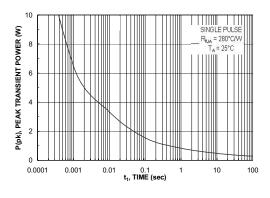


Figure 21. Single Pulse Maximum Power Dissipation

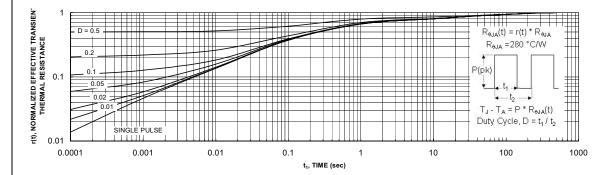


Figure 22. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

### **Dimensional Outline and Pad Layout** 1.70 1.50 A 0.50 \_0.30 0.15 0.50 В 1.20 BSC 1.60 1.80 1.25 □ 0.1 C B A (0.20)0.30 0.50 1.00 **TOP VIEW** LAND PATTERN RECOMMENDATION \_0.60 0.56 \_0.18 0.10 SEE DETAIL A C 0.35 BSC 0.20 BSC **DETAIL A** 0.10 SCALE 2:1 **BOTTOM VIEW** NOTES: A) THIS PACKAGE CONFORMS TO EIAJ SC89 PACKAGING STANDARD. B) ALL DIMENSIONS ARE IN MILLIMETERS. C) DRAWING CONFORMS TO ASME Y14.5M-1994 D) DIMENSIONS ARE EXCLUSIVE OF BURRS,

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